

Notice of References Cited

Application/Control No.

10/779,789

Applicant(s)/Patent Under
Reexamination
NAKAYAMA ET AL.

Examiner

Oanh Duong

Art Unit

2155

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0018713 A1	08-2001	Kokado et al.	709/235
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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